

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10071881	02/08/2002	250	311	2881	<i>Fernandez</i>

**APPLICANTS: Hosokawa Fumio; Nagayama Kuniaki; Danev Radostin;

**CONTINUING DATA VERIFIED:

None *KF*

** FOREIGN APPLICATIONS VERIFIED:
JAPAN 2001-033799 02/09/2001 *KF*

PG-PUB ☐ DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed ☒ yes ☐ no
35 USC 119 conditions met ☐ yes ☒ no
Verified and Acknowledged Examiners's initials *KF*

ATTORNEY DOCKET NO

116-020155

TITLE : Lens system for phase plate for transmission electron microscope and transmission electron microscope

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims <input type="checkbox"/> Print Claim for O.G. <input type="checkbox"/>
ISSUE FEE		Primary Examiner	DRAWING Sheets Drawn <input type="checkbox"/> Figs Drawn <input type="checkbox"/> Print Figs <input type="checkbox"/>
Amount Due	Date Paid		
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
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